IN THE CLAIMS

Cancel Claims 24, 25, 29, and 30 without prejudice and without disclaimer of subject matter.

Please amend Claims 26 and 31, and add new Claims 58-62, to read as follows. The amended claims are shown below as changed relative to original U.S. Patent 5,759,080.[1]

B1

26. (Amended) The method of Claim 23, wherein the metal is Pd.

B2

31. (Amended) The method of Claim 28, wherein the conductive material is selected from the group consisting of Pd and $SnO_2$.

B3

--58. (New) A method of fabricating an electron-emitting device which comprises a pair of electrodes and a layer disposed between the electrodes, the method comprising the steps of:

disposing the pair of electrodes in first and second regions on a substrate, respectively; and

providing the layer between the regions, the layer comprising a metal particle and a semiconductor,

wherein a diameter of the metal particle is in a range of several tens of angstroms to several micrometers.

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[1] Applicants understand that it is not necessary to include a marked-up version of the amended claims on any separate pages, since this is a reissue application (see, e.g., 37 C.F.R. §§ 1.121(h) and 1.173(b)).

59. (New) A method of fabricating an electron-emitting device, comprising the steps of:

disposing a pair of electrodes in first and second regions on a substrate, respectively; and

providing a layer between the regions, the layer comprising carbon and a metal particle,

wherein a diameter of the metal particle is in a range of several tens of angstroms to several micrometers.

B3 cont.

60. (New) The method of any one of Claims 58 and 59, wherein ~~the metal~~ particle ~~comprises~~ Pd.

61. (New) A method of fabricating an electron-emitting device, comprising the steps of:

disposing a pair of electrodes in first and second regions on a substrate, respectively; and

providing a layer between the regions, the layer comprising carbon and at least some conductive particles,

wherein diameters of the conductive particles are in a range of several tens of angstroms to several micrometers.

62. (New) The method of Claim 61, wherein the conductive particles comprise